

**Notice of References Cited**

Application/Control No.

10/735,210

Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,515,793	02-2003	Edagawa et al.	359/326
*	B	US-6,646,784	11-2003	Leuthold, Juerg	359/332
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	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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